

## Program-Announcement MUGM09 MunEDA User Group Meeting 2009 – Nov 12<sup>th</sup> & 13<sup>th</sup> Munich

*Dear MunEDA Friend & User,*

We are pleased to announce the program of our next MUGM MunEDA User Group Meeting 2009. MUGM09 will take place on 2009 November 12&13 (Thu/Fri) at City Hilton in Munich, Germany. Goal of the event is the intensive exchange of experience by industrial users but also an open forum for all technologists interested in MunEDA's DFM-DFY EDA software tools. Besides other contributions one main focus of the MunEDA User Group Meeting 2009 is the special topic:

## Methodologies for Time-Efficient Design, Rapid IP Porting and Technology Migration



**Date:** 2009 November 12&13 (Thu-Fri)  
**Location:** Hilton Munich City  
Rosenheimer Straße 15  
81667 Munich - Germany



### Selection of Technical & Presentation Topics of MUGM09:

- Handling Design Constraints & Sizing Rules
- IP Porting & Technology Migration
- Design Performance & Specification Analysis
- Response Surface Modelling & Model Generation
- Circuit Design Optimization & Verification
- Statistical Circuit Analysis & Optimization
- Multi-Testbench Environment & Corner Based Optimization
- Worst-Case Distance Analysis & Optimization
- Design Shrink & Nano-scale Circuit optimization
- Industrial Design Cases
- and much more topics ...

### MUGM & MTF Past & Future Forums:

- Seoul 2010
- **Munich 2009**
- Yokohama 2009
- Munich 2008
- Boston 2008
- Anaheim 2008
- Taiwan 2007
- Munich 2007
- Munich 2006
- Erfurt 2004
- <http://www.muneda.com/MUGM>

MunEDA User Group Meeting 2009 Agenda contains high-class and excellent technical contributions from leading semiconductor companies, fabless design houses, foundries, research institutes and universities like STMicroelectronics, Hynix, Infineon, Atmel, Bosch, ZMDI, STARC, Ulm University for Applied Sciences, Technische Universität München, TU Ilmenau, IMMS, Melexis, IPGen, NCU Taiwan and others ... (see program agenda on back side)

## Registration open at: [www.muneda.com/registration](http://www.muneda.com/registration)

We are very pleased to invite you to our MunEDA User Group Meeting 2009 in Munich.

**Andreas Ripp**

Vice President Sales & Marketing

AND YOUR

**MunEDA**

TEAM

**Dr. Michael Pronath**

Vice President Products & Solutions

Participation for MUGM2009 is free but early registration and accommodation is highly recommended as conference seats are limited.  
For accommodation refer to [http://www.muneda.com/MUGM-MTF-MTS\\_Europe-2009\\_Accommodation](http://www.muneda.com/MUGM-MTF-MTS_Europe-2009_Accommodation)

## MUGM Europe 2009 – Conference Program

## Day 1 – Thursday, November 12th, 2009

10:00 h - 10:30 h	<b>Registration &amp; Welcome Coffee</b>
10:30 h - 10:45 h	<b>Welcome &amp; What's new</b> Andreas Ripp, MunEDA GmbH, Munich, Germany
10:45 h - 11:30 h	<b>KEYNOTE - STARC - Tools, Trends &amp; Strategic Challenges for the Global Semiconductor Industry</b> Kunihiko Tsuboi, Semiconductor Technology Academic Research Center, Yokohama, Japan
11:30 h - 12:00 h	<b>STMicroelectronics: WiCkeD - An application of Worst Case Circuit Analysis and Yield Optimization in order to reveal circuit limitations - A Micro-Power Precision Operational Amplifier based on advanced Offset Cancellation Chopper Techniques in HF7CMOS (350 nm) from APM-IMS.</b> Angelo Ciccazzo, STMicroelectronics / MMS-CR&D, Catania, Italy
12:00 h - 13:30 h	<b>Lunch Break</b>
13:30 h - 13:55 h	<b>IPGEN: Automatic Analog IP Generation with: 1Stone®</b> Dirk Friebe, COO, IPGEN, Germany
13:55 h - 14:20 h	<b>STMicroelectronics – WiCkeD Application Case: Design and characterization of a dither VCO for mixed signal application at different level of abstraction</b> Antonio Colaci, STMicroelectronics, Automotive Products Group, Castelletto - Cornaredo, Italy
14:20 h - 15:05 h	<b>MunEDA: WiCkeD™ 6.0 – Software Tutorial &amp; Release Updates</b> Bernd Obermeier, MunEDA GmbH, Munich, Germany
15:05 h - 15:30 h	<b>BOSCH - Methods of Usage Measurement for WiCkeD in Bosch Automotive Design Flow</b> Michael Barth, Robert Bosch GmbH, Reutlingen, Germany
15:30 h - 16:00 h	<b>Coffee &amp; Discussion Break</b>
16:00 h - 16:30 h	<b>LANTIQ: The Stepchild Parametric Yield</b> Guntram E. Müller-L., Lantiq GmbH, Neubiberg, Germany
16:30 h - 17:00 h	<b>Atmel: Modelling of Multi-Stage Amplifiers with WiCkeD</b> Wolfgang Schneider, Hans-Werner Groh, Stefan Kern, Atmel Germany GmbH
17:00 h - 17:30 h	<b>Infineon: Architectural Assessment of Design Techniques to Improve Speed and Robustness in Embedded Microprocessor</b> Thomas Baumann, Infineon Technologies AG, Munich, Germany
17:30 h - 18:00 h	<b>IMMS: Analysis of frequency-optimized transimpedance amplifiers in XFAB 600nm BiCMOS technology</b> Dominik Krause, TU-Ilmenau/IMMS
From 19:00 h	<b>Social Event</b>

## Day 2 – Friday, November 13th, 2009

09:00 h - 09:30 h	<b>MunEDA Tools and R&amp;D-Roadmap</b> Frank Schenkel, VP Research & Development, MunEDA GmbH, Munich, Germany
09:30 h - 10:00 h	<b>STMicroelectronics: WiCkeD simulation based and modeling approach. A ring oscillator in 65nm non volatile memory technology from TRD-CCDS and a low</b> Elena Raciti, Central R&D, STMicroelectronics, Agrate, Italy
10:00 h - 10:30 h	<b>TUM Technische Universität München – Towards Reliability Optimization of Analog Integrated Circuits</b> Helmut Gräß, Technische Universität München, Germany
10:30 h - 11:00 h	<b>Coffee &amp; Discussion Break</b>
11:00 h - 11:25 h	<b>Hynix – Using WiCkeD in DRAM Development</b> Kwang-Seok Kim, Hynix Semiconductors, Korea
11:25 h - 11:50 h	<b>ZMDI: Analog IP Porting</b> Enno Böhme, ZMD AG, Dresden, Germany
11:50 h - 12:15 h	<b>NCU National Central University Taiwan - Analog Behavioral Modeling and its Application on Yield Enhancement of Analog Circuits</b> Chien-Nan (Jimmy) Liu (劉建男), National Central University Taiwan, Jung-Li, Taiwan, R.O.C.
12:15 h - 13:45 h	<b>Lunch Break</b>
13:45 h - 14:15 h	<b>STMicroelectronics: AMS design flow - Trends, strategic tools &amp; innovative methodologies for deep sub-micron technology nodes</b> Pierluigi Daglio, STMicroelectronics, Agrate, Italy
14:15 h - 14:45 h	<b>IMMS - Design and Optimization of a High-Speed Blu-ray Disc Photodetector IC with WiCkeD</b> Eckhard Hennig, IMMS GmbH, Erfurt, Germany
14:45 h - 15:15 h	<b>STMicroelectronics: WiCkeD - Statistical Analysis and Optimization of a Sense Amplifier for very low voltage applications in CMOS 90nm Flash technology from IMS MMS CR&amp;D</b> Mario Micciche, Alberto Di Martino, STMicroelectronics, Smart Card Group, Catania, Italy
15:15 h - 15:45 h	<b>Ulm University for Applied Science: Investigations on Performance and Productivity Improvement of CMOS Circuits for Analog Signal Processing with WiCkeD</b> Florian Mrugalla, Georg Vallant, Gerhard Forster, University for Applied Science Ulm, Germany
15:45 h - 16:15 h	<b>Coffee &amp; Discussion</b>
16:15 h - 17:45 h	<b>Expert Session: WiCkeD - Tool Demos, Q&amp;A &amp; Feedbacks</b> Bernd Lemaitre, Michael Pronath, MunEDA GmbH, Munich, Germany
At 17:45 h	<b>Conference End</b>